



2008 BIOINSPIRED DESIGN CONFERENCE

MISSISSIPPI STATE UNIVERSITY
HUNTER HENRY CENTER

AUGUST 19-22

CORPORATE SPONSORS PARTICIPATING THROUGH DEMOS/TUTORIALS:

Contact appropriate representative to schedule time and/or to bring individual samples.

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JEOL**Nikon Neoscope (JEOL) Tabletop SEM**Contact:

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Nikon Instruments**NeoScope (JEOL) Tabletop SEM
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Andre DeBellevue

501-908-6074

Adebellevue@nikon.net

Olympus

Olympus IX 81 Inverted research microscope with high resolution optics and an Olympus DSU Spinning disc confocal

The New Hamamatsu Orca R2 Hamamatsu ImagEM 512x512 Back thinned EMCCD and SlideBook Software (Quantitative Imaging software with Deconvolution capabilities)

Contact:

Charlie Cooper

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